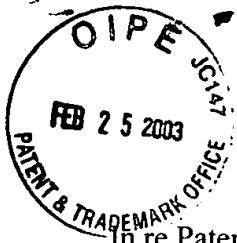


2882



PATENT

#16  
D. Scott  
6/19/03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS  
AND BARRIER LAYERS ON  
PATTERNED WAFERS WITH X-RAY  
REFLECTOMETRY

Confirmation No.:

Group Art Unit: 2876

Examiner: H.K. Song

**SUBMISSION OF FORMAL DRAWINGS**

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**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited  
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Washington, DC 20231 on February 18, 2003.

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Attn: Official Draftsperson  
Washington, D.C. 20231

STALLMAN & POLLOCK LLP

Dated: 02/18/2003

By:

Georgia K. Stith  
Georgia K. Stith

Sir:

Enclosed are three (3) sheets of formal drawings for filing in the above-referenced  
application.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Dated: February 18, 2003

By:

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Reg. No. 39,520

Attorneys for Applicant(s)

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